

# ISO/TR 14187:2011-08 (E)

## Surface chemical analysis - Characterization of nanostructured materials

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<b>Contents</b>		<b>Page</b>
Foreword .....		iv
Introduction .....		v
<b>1</b>	<b>Scope .....</b>	<b>1</b>
<b>2</b>	<b>Terms and definitions .....</b>	<b>1</b>
<b>3</b>	<b>Symbols and abbreviated terms .....</b>	<b>1</b>
<b>4</b>	<b>Characterization of nanostructured materials with surface analysis methods .....</b>	<b>3</b>
4.1	Introduction .....	3
4.2	Electron Spectroscopies (AES and XPS) .....	6
4.2.1	Surface functionalization and product formation .....	7
4.2.2	Presence of contamination and coatings .....	8
4.2.3	Orientation of surface molecules .....	8
4.2.4	Coating or layer thickness .....	8
4.2.5	Near-surface elemental distribution .....	10
4.2.6	Particle size .....	10
4.2.7	Particle location, composition and shape .....	11
4.2.8	Other properties: electronic characteristics and surface acidity .....	11
4.3	Ion-beam surface analysis methods (SIMS and LEIS) .....	12
4.3.1	SIMS and examples of SIMS applications .....	12
4.3.2	Low energy ion scattering and applications to nanomaterials .....	13
4.4	Scanning probe microscopy .....	14
4.5	Surface characterization of carbon nanostructures .....	15
<b>5</b>	<b>Analysis considerations, issues and challenges associated with characterization of nanostructured materials: Information for the analyst .....</b>	<b>15</b>
5.1	Introduction .....	15
5.2	General considerations and analysis challenges .....	16
5.3	Physical properties .....	17
5.4	Particle stability and damage: influence of size, surface energy and confluence of energy scales .....	18
5.4.1	Crystal structure .....	18
5.4.2	Damage and probe effects .....	19
5.4.3	Time and environment .....	19
5.5	Sample mounting and preparation considerations .....	24
5.6	Specific considerations for analysis of nanostructured materials using XPS, AES, SIMS and SPM .....	24
5.6.1	Introduction .....	24
5.6.2	Issues related to application of XPS to nanomaterials .....	24
5.6.3	Issues related to the application of AES to nanostructured materials .....	27
5.6.4	Issues related to application of SIMS to nanoparticles .....	27
5.6.5	Issues related to the application of scanning probe methods to nanoparticles .....	29
<b>6</b>	<b>General characterization needs and opportunities for nanostructured materials .....</b>	<b>29</b>
Bibliography .....		31